



**NTE5514 thru NTE5516**  
**Silicon Controlled Rectifier (SCR)**  
**20 Amp, 1/2" Press Fit**

**Absolute Maximum Ratings:**

Repetitive Peak Off-State Voltage ( $T_J = +100^\circ\text{C}$ ),  $V_{\text{DRM}}$

NTE5514 .....	200V
NTE5515 .....	400V
NTE5516 .....	600V

Repetitive Peak Reverse Voltage ( $T_J = +100^\circ\text{C}$ ),  $V_{\text{RRM}}$

NTE5514 .....	200V
NTE5515 .....	400V
NTE5516 .....	600V

RMS On-State Current ( $T_C = +75^\circ\text{C}$ ),  $I_T(\text{RMS})$  .....

Peak Surge (Non-Repetitive) On-State Current (One Cycle, 50Hz or 60Hz),  $I_{\text{TSM}}$  .....

Peak Gate-Trigger Current (3μs Max),  $I_{\text{GTM}}$  .....

Peak Gate-Power Dissipation ( $I_{\text{GT}} \leq I_{\text{GTM}}$  for 3μs Max),  $P_{\text{GM}}$  .....

Average Gate-Power Dissipation,  $P_{\text{G(AV)}}$  .....

Operating Temperature Range,  $T_{\text{opr}}$  .....

Storage Temperature Range,  $T_{\text{stg}}$  .....

Typical Thermal Resistance, Junction-to-Case,  $R_{\text{thJC}}$  .....

**Electrical Characteristics:** (At Maximum Ratings and Specified Case Temperatures)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Peak Off-State Current	$I_{\text{DRM}}, I_{\text{RRM}}$	$T_J = +100^\circ\text{C}$ , Gate Open, $V_{\text{DRM}}$ and $V_{\text{RRM}} = \text{Max. Rating}$	-	-	2.0	mA
Maximum On-State Voltage (Peak)	$V_{\text{TM}}$	$T_C = +25^\circ\text{C}$	-	-	1.9	V
Peak On-State Current	$I_{\text{TM}}$		-	-	40	A
DC Holding Current	$I_H$	$T_C = +25^\circ\text{C}$ , Gate Open	-	-	50	mA
DC Gate-Trigger Current	$I_{\text{GT}}$	Anode Voltage = 12V, $R_L = 30\Omega$ , $T_C = +25^\circ\text{C}$	-	-	25	mA
DC Gate-Trigger Voltage	$V_{\text{GT}}$	Anode Voltage = 12V, $R_L = 30\Omega$ , $T_C = +25^\circ\text{C}$	-	-	2.0	V
Gate Controlled Turn-On Time	$t_{\text{gt}}$	$t_d + t_r$ , $I_{\text{GT}} = 150\text{mA}$	-	2.5	-	μs
Critical Rate-of-Rise of Off-State Voltage	Critical $dv/dt$	$T_C = +100^\circ\text{C}$ , Gate Open	-	100	-	V/μs

